Issue	Classification	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/019,332	SHINO ET AL.	
Examiner	Art Unit	
Danny Wai Lun Leung	2633	

ISSUE CLASSIFICATION																					
ORIGINAL									CROSS REFERENCE(S)												
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INTERNATIONAL CLASSIFICATION			1							$\neg \dagger$			*****	+		 					
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January (Date)							JASON CHAN SUPERVISORY PATENT EXAMINER SUPERVISORY CENTER 2600								Total Claims Allowed: 6						
	SUPERVISORY FALLY TECHNOLOGY CENTER 2600 Print Claim(s) (Primary Examiner) (Date)										O.G. Print Fig.										
	☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐											□ R	1.47								
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